



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**P -CHANNEL ENHANCEMENT MODE POWER MOSFET****TF110P03N****• General Description**

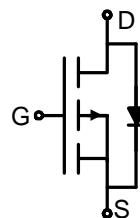
The TF110P03N combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ .

**• Features**

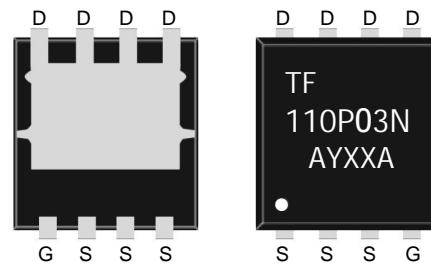
- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

**• Application**

- Load Switch
- PWM Application
- BLDC Motor driver

**• Product Summary**

$V_{DS} = -30V$     $I_D = -42A$   
 $R_{DS(on)(-10V typ)} = 11m\Omega$   
 $R_{DS(on)(-4.5V typ)} = 14m\Omega$

**PDFNWB5x6-8L****• Ordering Information:**

Part NO.	TF110P03N
Marking1	TF110P03N
Marking2	TF:tuofeng; Y:year code; XX:Week; AA:device code;
Basic ordering unit (pcs)	5000

**• Absolute Maximum Ratings ( $T_C = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	-42	A
	$I_D @ T_C = 75^\circ C$	-30	A
	$I_D @ T_C = 100^\circ C$	-25	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	-96	A
Total Power Dissipation <sup>②</sup>	$P_D @ T_C = 25^\circ C$	35	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	1.5	W
Operating Junction Temperature	$T_J$	-55 to 150	°C
Storage Temperature	$T_{STG}$	-55 to 150	°C



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**P -CHANNEL ENHANCEMENT MODE POWER MOSFET****TF110P03N****•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case <sup>②</sup>	R <sub>thJC</sub>	-	-	7.5	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	65	° C/W
Soldering temperature, wavesoldering for 8s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics(T<sub>j</sub>=25 °C, unless otherwise note)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	-30			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.0	-1.5	-2.0	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =-28V, V <sub>GS</sub> =0V			-1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-16A		11	15	mΩ
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-10A		14	20	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A		12		S
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =-10A		0.85	1.00	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	f = 1MHz V <sub>DD</sub> = -15V V <sub>GS</sub> = 0V	-	1716	-	pF
Output capacitance	C <sub>oss</sub>		-	226.9	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	196.6	-	

**•Gate Charge characteristics(T<sub>a</sub> = 25°C)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = -15V I <sub>D</sub> = -15A V <sub>GS</sub> = -10V	-	36.9	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	6.17	-	
Gate - Drain charge	Q <sub>gd</sub>		-	5.97	-	
Body Diode Reverse Recovery Time	T <sub>rr</sub>	I <sub>F</sub> =15A, di/dt=100A/μs		17		nS
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			45		nC

Note:

① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;

Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;

Fig.1 Gate-Charge Characteristics

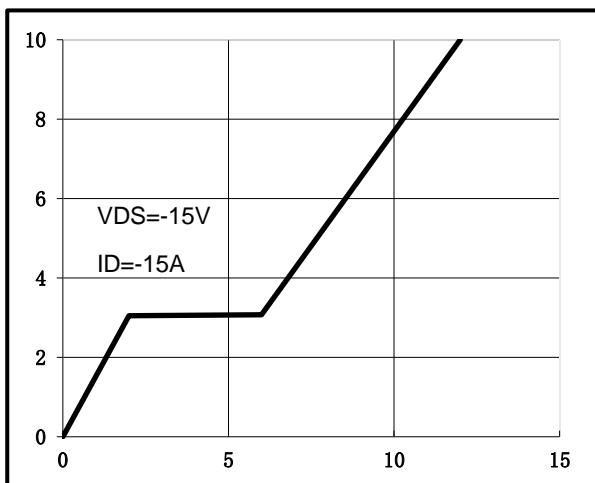


Fig.2 Capacitance Characteristics

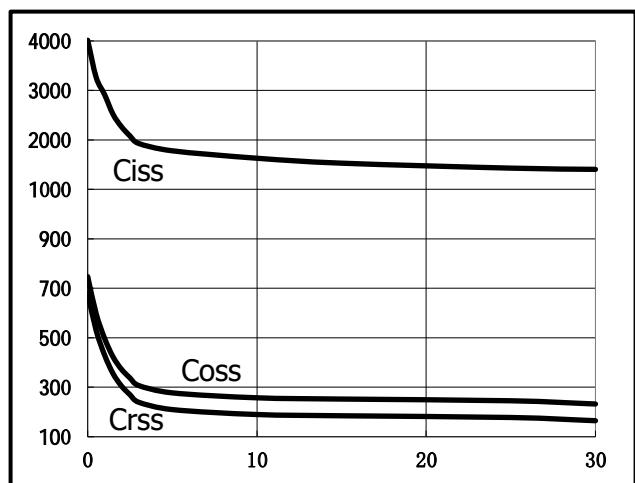


Fig.3 Power Dissipation Derating Curve

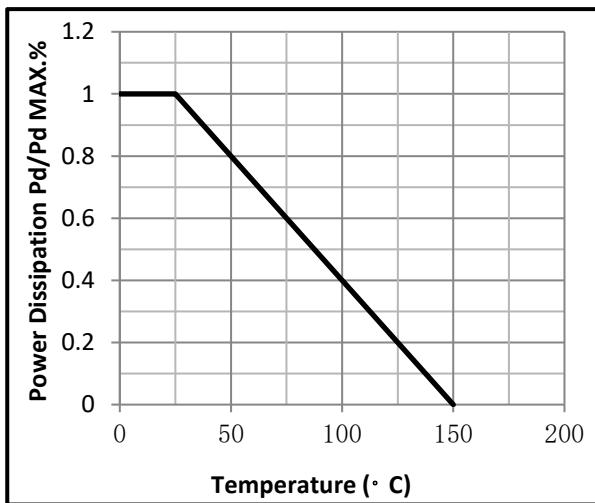


Fig.4 Typical output Characteristics

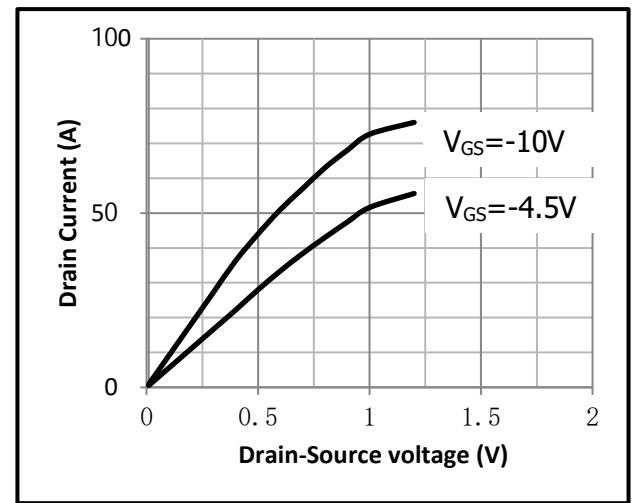


Fig.5 Threshold Voltage V.S Junction Temperature

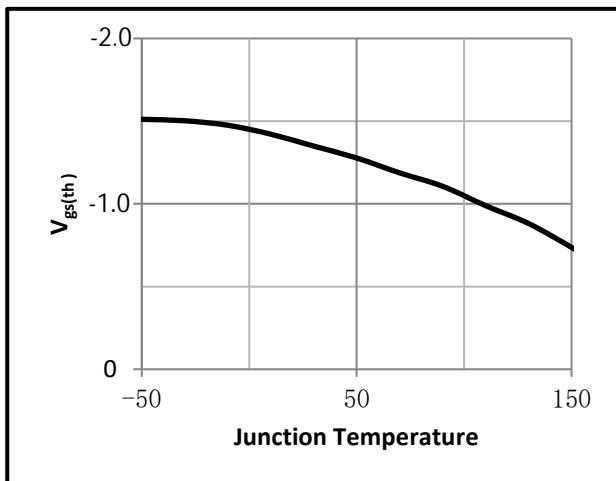


Fig.6 Resistance V.S Drain Current

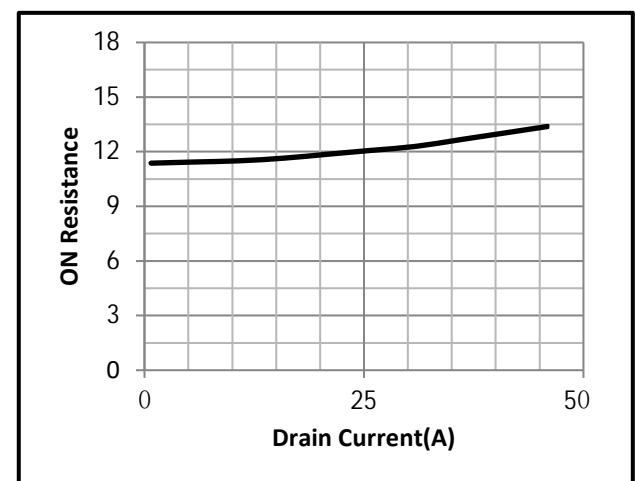


Fig.7 On-Resistance VS Gate Source Voltage

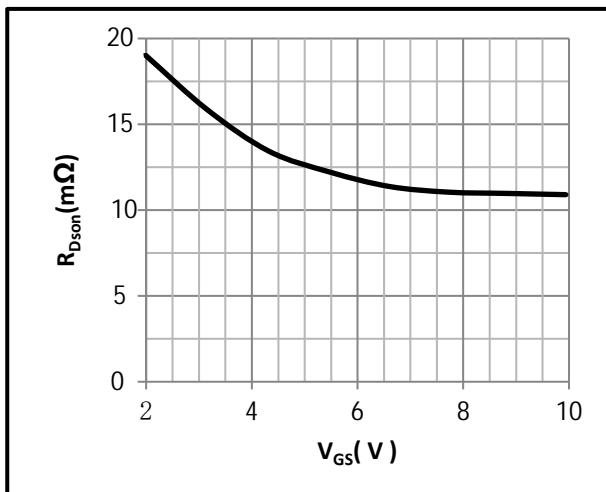


Fig.8 On-Resistance V.S Junction Temperature

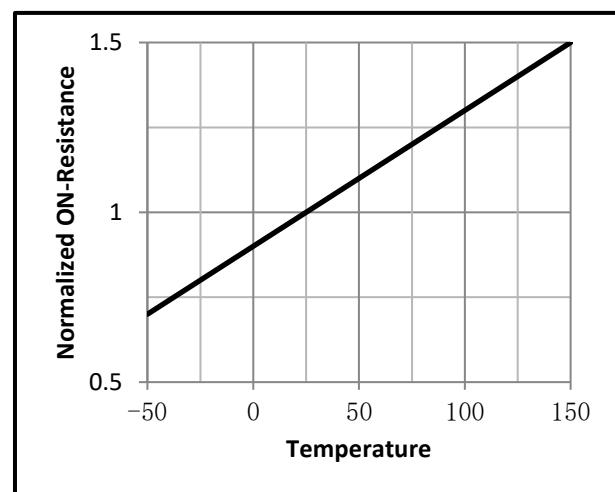


Fig.9 Switching Time Measurement Circuit

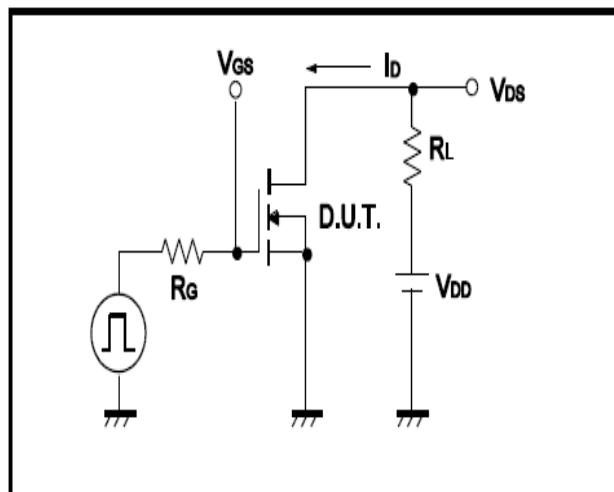


Fig.10 Gate Charge Waveform

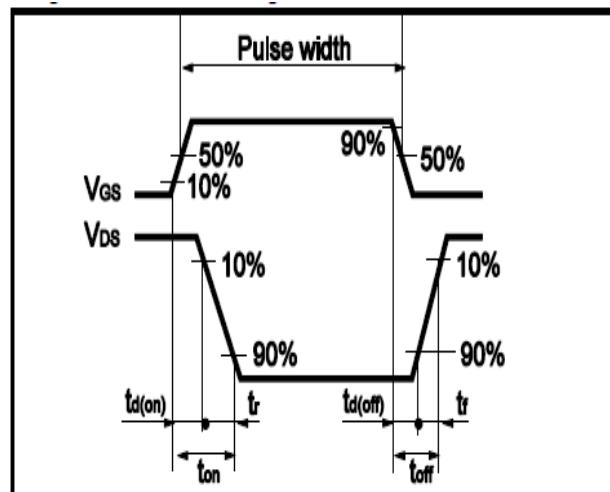


Fig.11 Avalanche Measurement Circuit

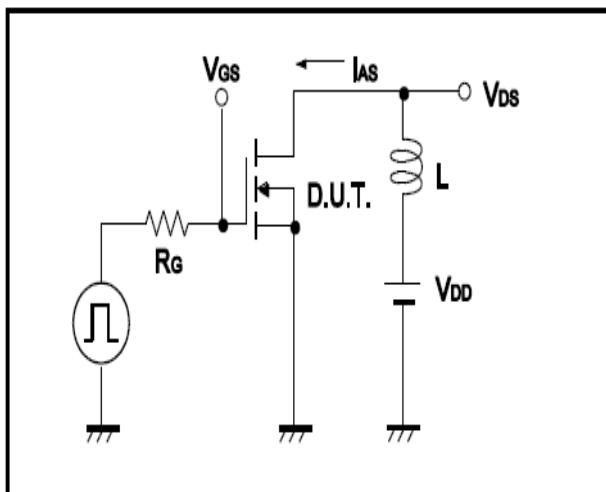
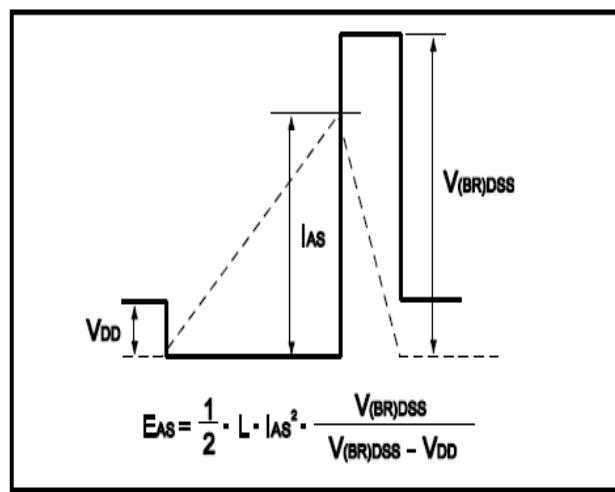


Fig.12 Avalanche Waveform



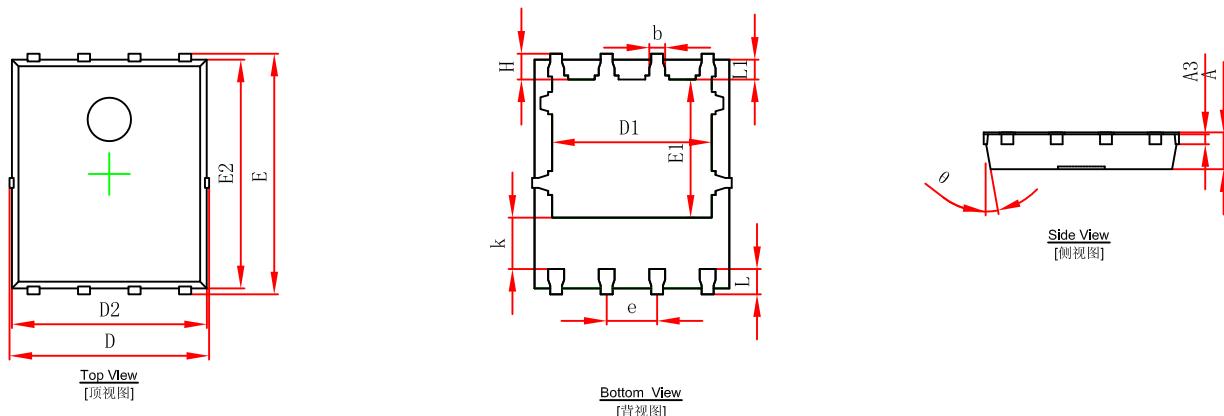


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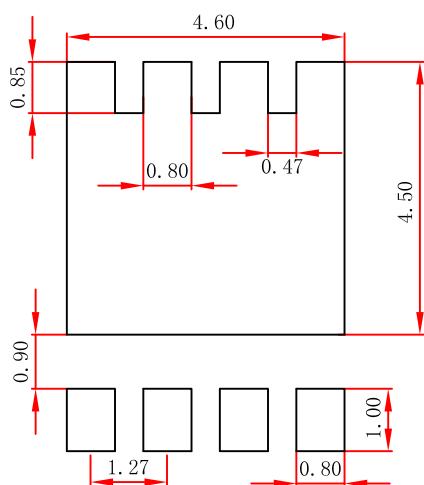
TF110P03N

## PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

## PDFNWB5x6-8L Suggested Pad Layout



## Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.